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1	3	(5,002,730 6,511,925 6,498,714).pn.	USPAT	2004/03/19 14:34
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-	750	hafnium.clm. and semiconductor	USPAT	2004/03/19 12:34
-	2328	438/240.CCLS. 438/396.ccls. 438/785.ccls.	USPAT	2004/03/19 13:02
-	145	(438/240.CCLS. 438/396.ccls. 438/785.ccls.) and "hafnium"	USPAT	2004/03/19 12:54
-	5	(US-6274454-\$ or US-5079191-\$ or US-5552337-\$ or US-5633188-\$ or US-5753945-\$).did.	USPAT	2004/03/19 12:54
-	1	5122477.pn.	USPAT	2004/03/19 12:57
-	298305	hafnium with10 (diffusion barrier)	USPAT	2004/03/19 12:57
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*Ota, H.; Migita, S.; Morita, Y.; Sakai, S.;*

Gate Insulator, 2001. IWGI 2001. Extended Abstracts of International Workshop on , 1-2 Nov. 2001

Pages:188 - 190

[\[Abstract\]](#)   [\[PDF Full-Text \(206 KB\)\]](#)   IEEE CNF

#### 2 Characteristics of high quality hafnium oxide gate dielectric

*Zhan, N.; Ng, K.L.; Poon, M.C.; Kok, C.W.; Chan, M.; Wong, H.;*

Electron Devices Meeting, 2002. Proceedings. 2002 IEEE Hong Kong , 22 June 2002

Pages:43 - 46

[\[Abstract\]](#)   [\[PDF Full-Text \(271 KB\)\]](#)   IEEE CNF

#### 3 Characterization and comparison of high-k metal-insulator-metal (MiM) capacitors in 0.13 $\mu\text{m}$ Cu BEOL for mixed-mode and RF applications

*Tu, Y.L.; Lin, H.L.; Chao, L.L.; Wu, D.; Tsai, C.S.; Wang, C.; Huang, C.F.; Lin, C.H.; Sun, J.;*

VLSI Technology, 2003. Digest of Technical Papers. 2003 Symposium on , 10-12 June 2003

Pages:79 - 80

[\[Abstract\]](#)   [\[PDF Full-Text \(277 KB\)\]](#)   IEEE CNF

#### 4 Enhanced tunnel magnetoresistance by hf-layer insertion in the AlO/sub x/ tunnel barriers

*Byong Guk Park; Taek Dong Lee;*

Magnetism, IEEE Transactions on , Volume: 38 , Issue: 5 , Sept. 2002

Pages:2706 - 2708

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**5 Low-resistance spin-dependent tunnel junctions with HfAlO/sub x/ barriers for high-density recording-head application**

Jianguo Wang; Freitas, P.P.; Snoeck, E.; Batlle, X.; Cuadra, J.;  
Magnetics, IEEE Transactions on , Volume: 38 , Issue: 5 , Sept. 2002  
Pages:2703 - 2705

[\[Abstract\]](#) [\[PDF Full-Text \(202 KB\)\]](#) IEEE JNL

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**6 Current transport in metal/hafnium oxide/silicon structure**

Zhu, W.J.; Tso-Ping Ma; Tamagawa, T.; Kim, J.; Di, Y.;  
Electron Device Letters, IEEE , Volume: 23 , Issue: 2 , Feb. 2002  
Pages:97 - 99

[\[Abstract\]](#) [\[PDF Full-Text \(65 KB\)\]](#) IEEE JNL

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**7 Low resistance spin-dependent tunnel junctions with HfAlO/sub x/- barriers for MTJ recording head application**

Jianguo Wang; Freitas, P.P.;  
Magnetics Conference, 2002. INTERMAG Europe 2002. Digest of Technical Papers.  
2002 IEEE International , 28 April-2 May 2002  
Pages:DE2

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**8 Theoretical and experimental investigation of Si nanocrystal memory device with HfO/sub 2/ high-k tunneling dielectric**

Lee, J.J.; Wang, X.; Bai, W.; Lu, N.; Liu, J.; Kwong, D.L.;  
VLSI Technology, 2003. Digest of Technical Papers. 2003 Symposium on , 10-12  
June 2003  
Pages:33 - 34

[\[Abstract\]](#) [\[PDF Full-Text \(302 KB\)\]](#) IEEE CNF

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**9 Enhanced tunnel magnetoresistance by Hf layer insertion in the tunnel barriers**

Park, B.G.; Lee, T.D.;  
Magnetics Conference, 2002. INTERMAG Europe 2002. Digest of Technical Papers.  
2002 IEEE International , 28 April-2 May 2002  
Pages:DE3

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**10 Theoretical and experimental investigation of Si nanocrystal memory device with HfO/sub 2/ high-k tunneling dielectric**

Jong Jin Lee; Xuguang Wang; Weiping Bai; Nan Lu; Dim-Lee Kwong;  
Electron Devices, IEEE Transactions on , Volume: 50 , Issue: 10 , Oct. 2003  
Pages:2067 - 2072

[\[Abstract\]](#) [\[PDF Full-Text \(854 KB\)\]](#) IEEE JNL

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**11 Robust HfN metal gate electrode for advanced MOS devices application**

Yu, H.Y.; Lim, H.F.; Chen, J.H.; Li, M.F.; Zhu, C.X.; Kwong, D.-L.; Tung, C.H.;  
Bera, K.L.; Leo, C.J.;  
VLSI Technology, 2003. Digest of Technical Papers. 2003 Symposium on , 10-12  
June 2003  
Pages:151 - 152



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